# Today

### 3/22/11 Lecture 9

### Analog $\Leftrightarrow$ Digital Conversion

- Sampled Data Acquisition Systems
- Discrete Sampling and Nyquist
- Digital to Analog Conversion
- Analog to Digital Conversion

### Homework

- Study for Exam next week (in class 3/29/11)
- Covers everything up through Lecture 8 and Lab 7

### Reading

• A/D converters (pages 612-641).

### Lab

- Do DAC pre-lab before lab meeting.
  - Graded at start of lab!!!
- Sequential logic lab book due 3/25 at 10am.

# Analog $\rightarrow$ Digital $\rightarrow$ Analog

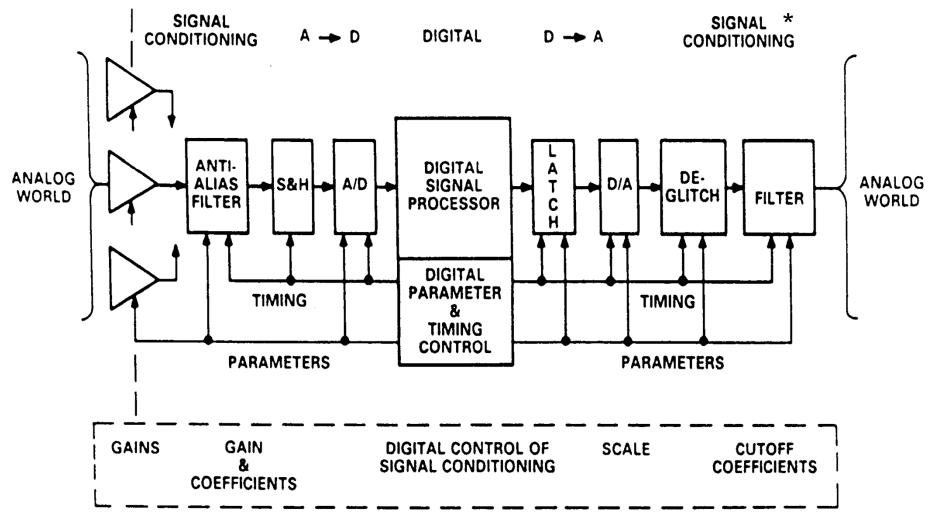
### Why convert from analog to digital

- Digital transmission and storage of analog signals
  - Compression, Reliability, Error Correction
- Digital signal processing
  - Powerful algorithm, adaptable, ease of implementation

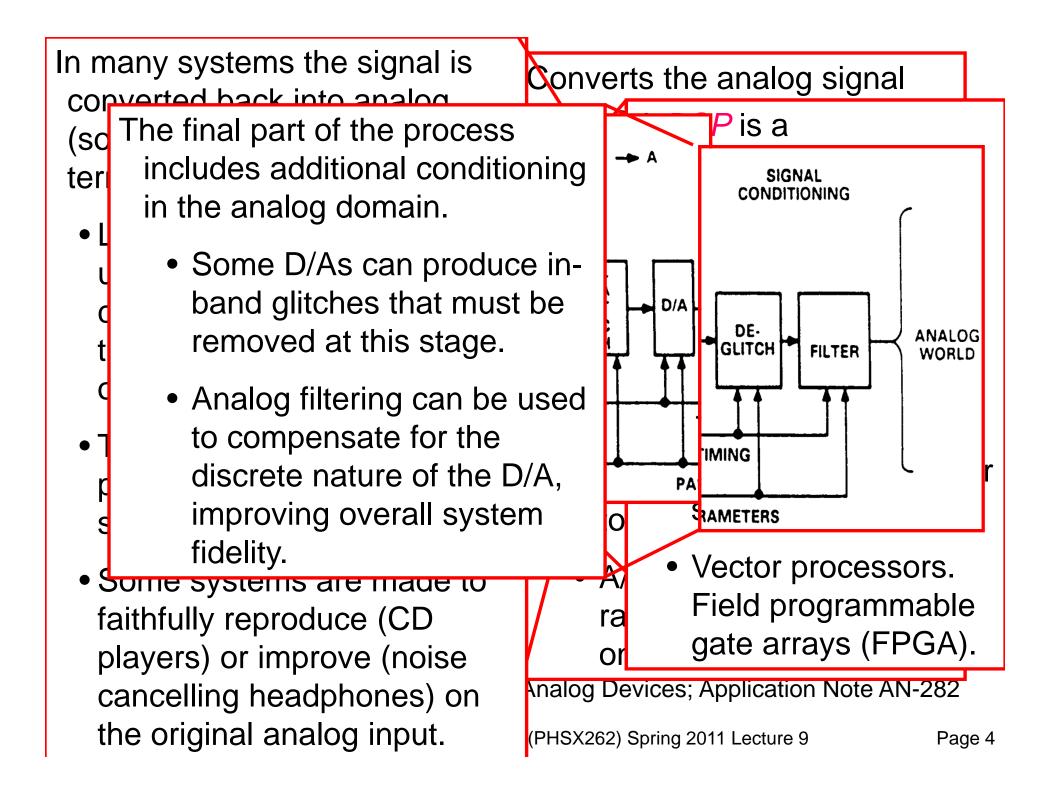
### Why convert from digital to analog

- We live (see, hear, and feel) in an analog world
- Replay stored, transmitted, or processed data
  - Music, messages, movies
- Relay information from computers to humans
- Digital control of analog systems
- Convert virtual worlds to reality

### Key Elements of a Sampled Signal Processing System

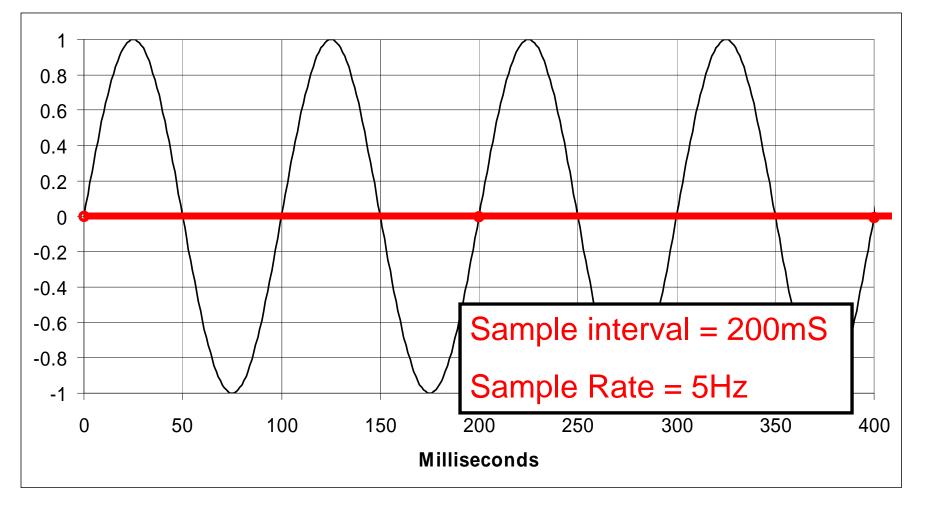


\*ref: Analog Devices; Application Note AN-282

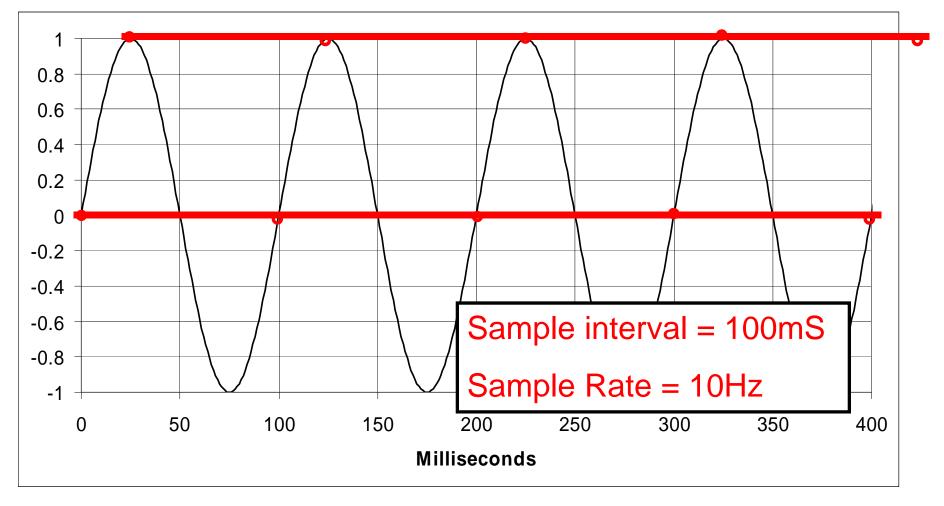


### Discrete Sampling of 10 Hz Signal at 5Hz

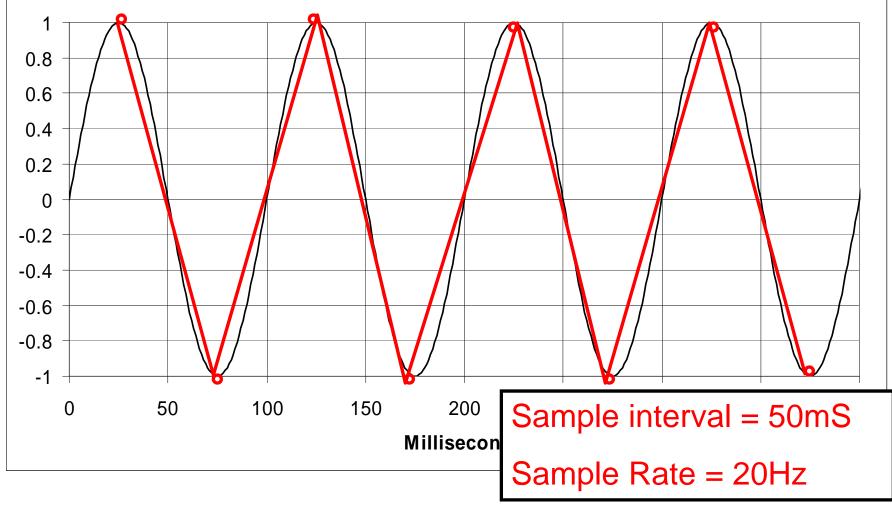
$$f_{Signal} = 10Hz$$
  $f_{Sample} = 5Hz$ 



## Discrete Sampling of 10Hz signal at 10Hz $f_{Signal} = 10Hz$ $f_{Sample} = 10Hz$





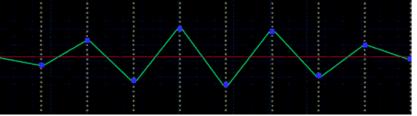


Based with permission on lectures by John Getty

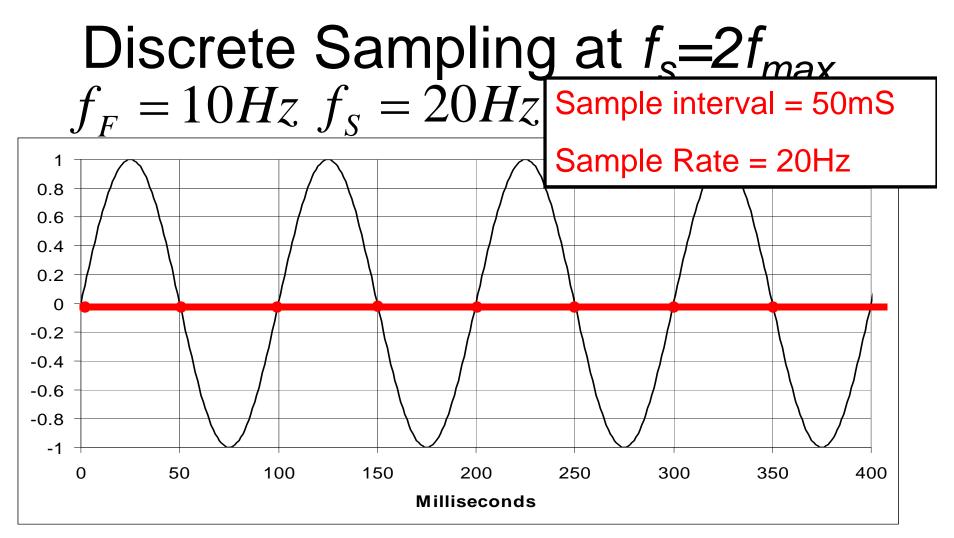
# Nyquist Sampling Theorem

The sampling theorem states that for a limited bandwidth (band-limited) signal with maximum frequency  $f_{max}$ , the equally spaced sampling frequency  $f_{sample}$  must be GREATER THAN twice the maximum frequency of the signal,  $f_{max}$ , in order to uniquely reconstruct the signal without *aliasing*.

$$f_{sample} > 2 f_{\max}$$



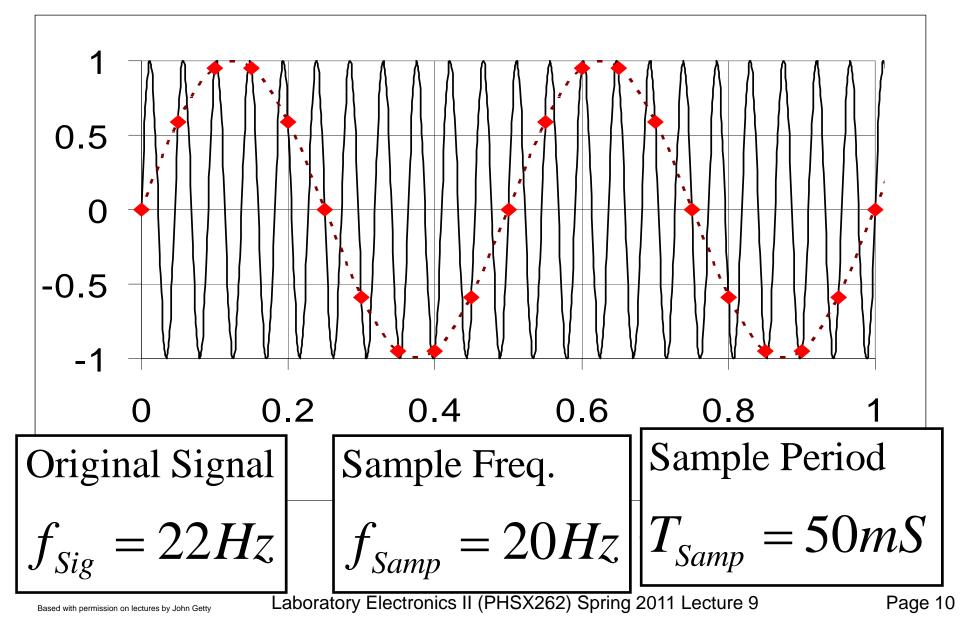
=> 2*f<sub>max</sub>* is called the *Nyquist sampling rate*. Half of the sampling rate of an A/D is sometimes called its **Nyquist frequency**, and is the max frequency that a A/D can record.



 $f_s=2f_{max}$  is not sufficient,

Nyquist sampling requires  $f_{s} > 2f_{max}$ 

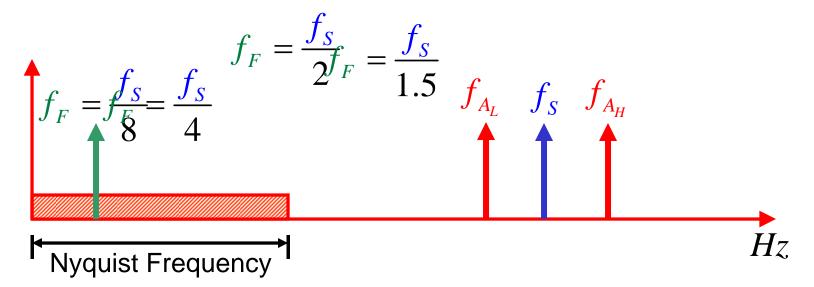
# Aliasing



### Aliasing in the Frequency Domain

The frequency of aliased signals is the difference between and sum of the sampling frequency  $f_S$  and signal being sampled,  $f_F$ . These aliased signals repeat around each integer multiple of the sampling frequency.

$$f_{A_L} = f_S - f_F$$
 and  $f_{A_H} = f_S + f_F$ 



If you low pass filtered at  $f_s$ , the you know only  $f < f_s$  are real.

Digital to Analog Converter (DAC) Terminology *Number of Bits:* 

A DAC with *n* bits provides  $2^n$  discrete output steps or *counts*. For example an 8 bit DAC has 256 possible output values.

#### Output Range:

Difference between the maximum and minimum output values.

#### Resolution:

Also known as the "step size", represents the minimum change in output voltage. Typically equal to output range /  $(2^{n}-1)$ 

#### Dynamic Range:

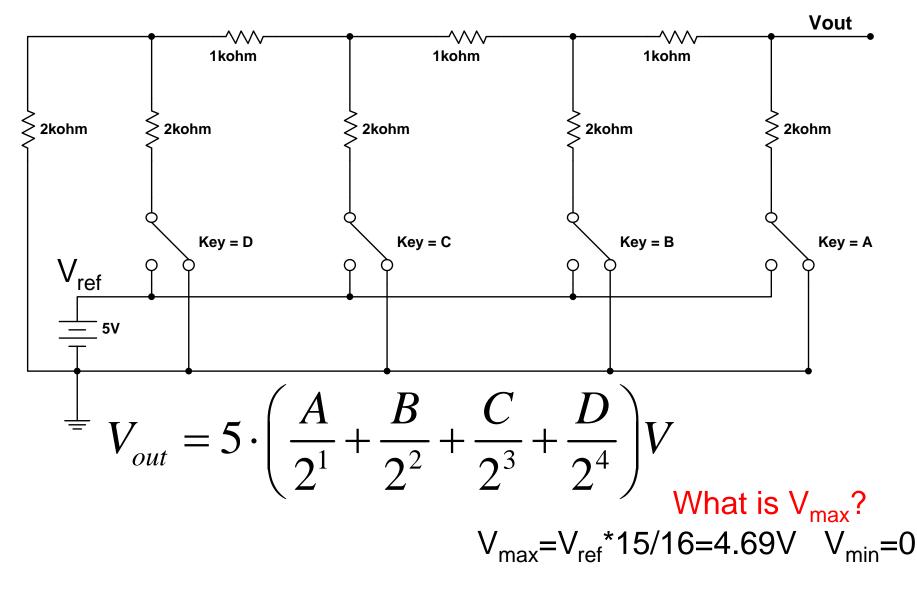
Output Range divided by Resolution or Noise Voltage. Would be (2<sup>n</sup>-1) if the noise was less than step size of DAC.

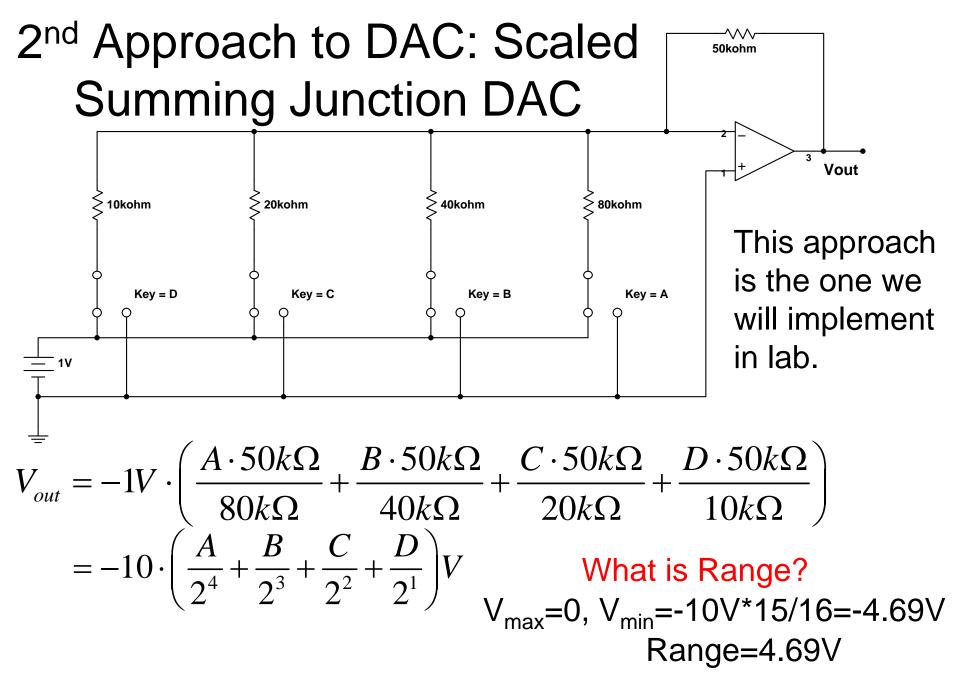
### **In-Class Exercise**

Assume a 10 bit DAC is set up to output a voltage from  $-12V_{dc}$  to  $+12V_{dc}$ . Determine the resolution.



### One Approach to DAC: R-2R Ladder Circuit





Analog to Digital Converter (ADC) Terminology *Number of Bits:* 

An ADC with *n* bits divides the input range into  $2^n$  discrete steps. For example, an 8 bit ADC can produce a total of 256 different output codes.

#### Full Scale Input Range

Difference between the minimum and maximum input voltage that can be measured.

#### Resolution:

Quantization, also known as the "step size", is the change in input voltage represented by each count at the output. Often referred to as LSB (least significant bit)

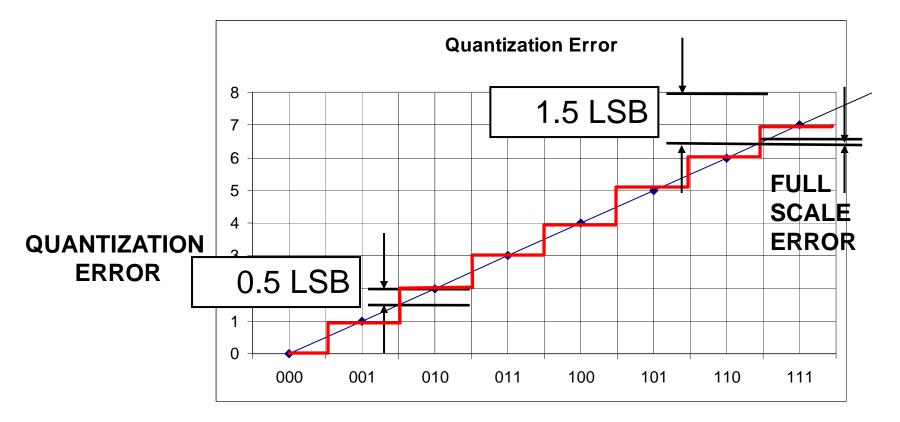
#### Dynamic Range:

Input Range divided by resolution or noise. Typically equals 2<sup>n</sup>-1, if noise is less than LSB.

# ADC Accuracy

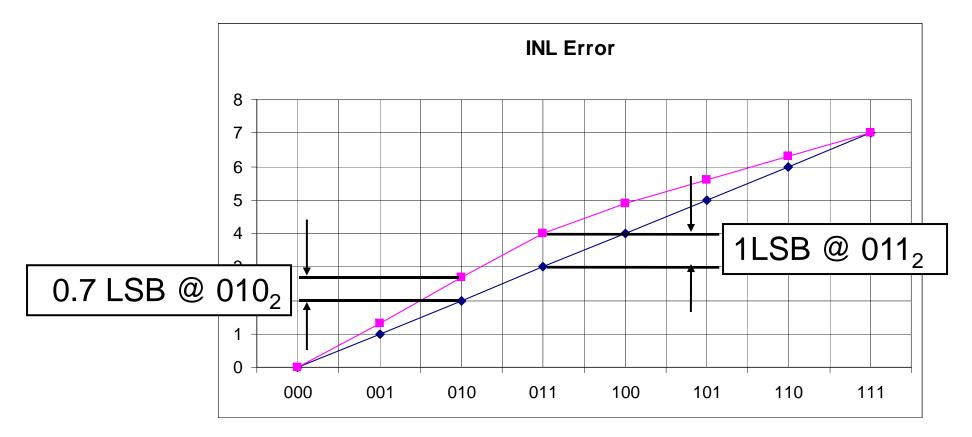
- **QUANTIZATION ERROR** Inherent accuracy (±1/2LSB, least significant bit)
- INTEGRAL NON-LINEARITY (INL) is a measure of the deviation of each individual code from a line drawn from zero scale or negative full scale (1/2 LSB below the first code transition) through positive full scale (1/2 LSB above the last code transition). The deviation of any given code from this straight line is measured from the center of that code value.
- **DIFFERENTIAL NON-LINEARITY (DNL)** is the measure of the maximum deviation from the ideal step size of 1 LSB. DNL is commonly measured at the rated clock frequency with a ramp input.
- **MISSING CODES** are output codes that are skipped or never appear at the ADC outputs. These codes cannot be reached by any input value.
- **OFFSET ERROR** is the difference between the ideal and actual LSB transition point.
- FULL SCALE ERROR is how far the last code transition is from the ideal 1.5 LSB below positive V\_ref (V\_ref is 2<sup>n</sup> times step size)
- GAIN ERROR is number of LSB "gained" from conversion from lowest to highest output. It is a measure of the deviation of the ADC from linear (gain = 1) conversion. See figure 9.44 in H&H page 615

# Ideal ADC: Quantization Error



-Quantization error is the inherent deviation of the output from a straight line. -Note last transition is 1.5 LSB from  $V_{ref}$  (used to measure full scale error)

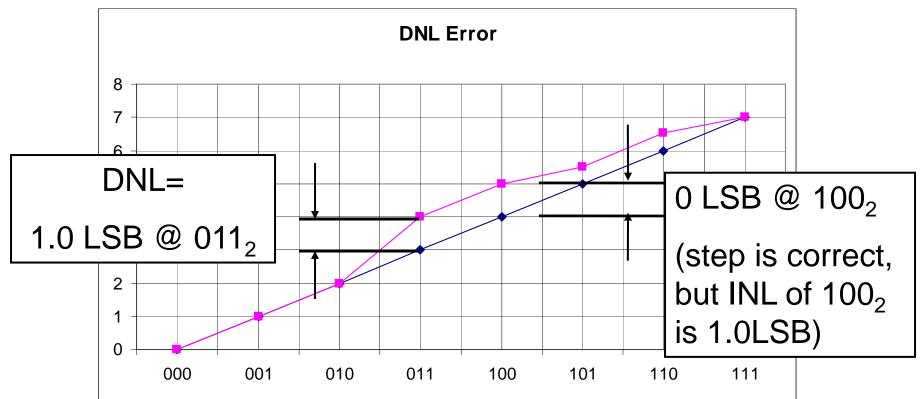
# Sampled System Errors - INL



Integral Non-Linearity is the deviation of the output from a straight line.

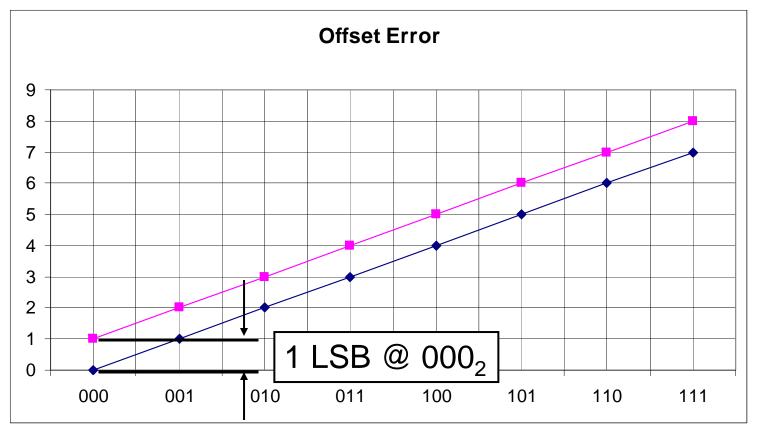
Can be measured at each code or stated as maximum for all codes.

# Sampled System Errors - DNL



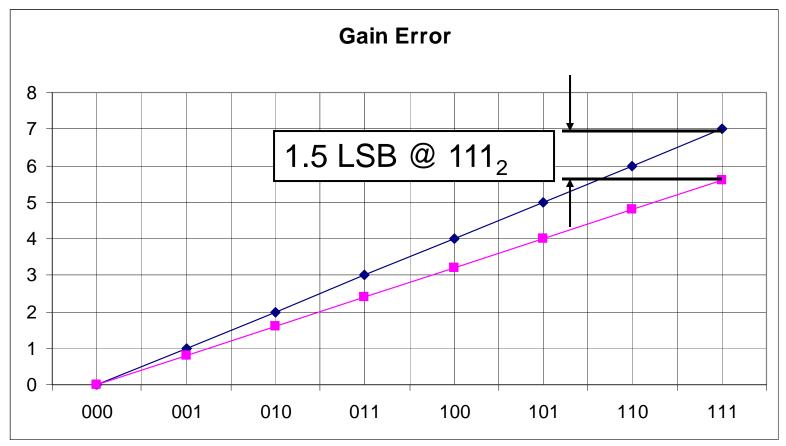
*Differential Non-Linearity* is the maximum difference between the expected stepsize (1 LSB) and that steps actually produced by the DAC.

## Sampled System Errors - Offset



Offset Error is measured at  $000_2$ .

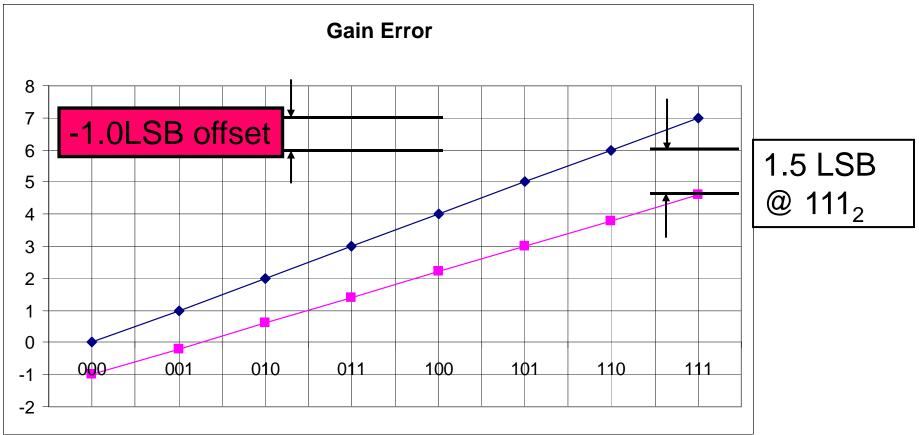
# Sampled System Errors - Gain



*Gain Error* is measured at 111<sub>2</sub>.

The offset error must be known to compute slope. (*y=mx+b*) *Gain Error* is given in LSB over full scale.

## Sampled System Errors - Gain



*Gain Error* is measured at 111<sub>2</sub>.

The offset error must be known to compute this value. (y=mx+b)

### References

- 1. Paul Horowitz and Winfield Hill (1989). "The Art of Electronics," 2<sup>nd</sup> Ed., Cambridge
- 2. Analog Devices, "Fundamentals of Sampled Data Systems", accessed MAR 2008 http://www.analog.com/en/cat/0,2878,760,00.html
- 3. "Efunda, Engineering Fundamentals" web site; accessed MAR 2008 http://www.efunda.com/designstandards/sensors/methods/DSP\_nyquist.cfm
- 4. National Semiconductor: accessed MAR 2008 http://www.national.com/appinfo/adc/files/definition\_of\_terms.pdf